

Notice of References Cited	Application/Control No. 09/772,728	Applicant(s)/Patent Under Reexamination TANIMOTO, HIROYOSHI	
	Examiner Mary C Hogan	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hurkx et al, "A New Analytical Diode Model Including Tunneling and Avalanche Breakdown", IEEE Transactions on Electron Devices, Vol. 39, No. 9, September 1992
	V	Hurkx et al, "A New Recombination Model for Device Simulation Including Tunneling", IEEE Transactions on Electron Devices, Vol. 93, No. 2, February 1992.
	W	
	X	

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